

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of
MARSHALL et al.

Serial No. 09/923,341

Filed: August 8, 2001

For: PHOTODETECTOR CIRCUIT



Atty. Ref.: 124-880

Group: 2815

Examiner: Joseph Nguyen

* * * * *

April 16, 2003

Assistant Commissioner for Patents
Washington, DC 20231

Sir:

INFORMATION DISCLOSURE STATEMENT

As suggested by 37 C.F.R. 1.97, the undersigned attorney brings to the attention of the Patent and Trademark Office the reference listed on the attached form PTO-1449, a copy of each of which is enclosed. This is not to be construed as a representation that a search has been made or that no better prior art exists, or that a reference is relevant merely because cited.

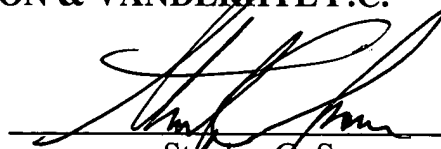
The Examiner is requested to initial the attached form PTO-1449 and to return a copy of the initialed document to the undersigned as an indication that the attached reference has been considered and made of record.

Pursuant to Rule 37 C.F.R. §1.97(c), a fee of \$180.00 as specified in Rule 17(p) is attached. If there is any shortage in the fee, please charge the deposit account of Nixon & Vanderhye, Account No. 14-1140.

Respectfully submitted,

NIXON & VANDERHYE P.C.

By:


Stanley C. Spooner
Reg. No. 27,393

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Serial No. 09/923,341

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INFORMATION DISCLOSURE
CITATION

ATTY. DOCKET NO.

124-880

APPLICANT

MARSHALL et al.

FILING DATE

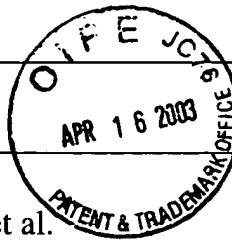
August 8, 2001

SERIAL NO.

09/923,341

GROUP

2815



(Use several sheets if necessary)

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO

OTHER DOCUMENTS (including Author, Title, Date, Pertinent pages, etc.)

	~	S.M. Sze VLSI Technology pp. 482-485
	~	Spinelli et al IEEE Transactions on Electron Devices, Vol. 44, No. 11, Nov. 1997 pp. 1931-1943 Physics and Numerical Simulation of Single Photon Avalanche Diodes
	~	Jackson et al Proc. IEEE 2001 Int. Conference on Microelectronic Test Structures, Vol. 14, March 2001 pp. 165-170 Process Monitoring and Defect Characterization of Single Photon Avalanche Diodes

*Examiner

Date Considered

Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application.

Form PTO-FB-A820 (Also PTO-1449)